

PATENT APPLICATION

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IN THE U.S. PATENT AND TRADEMARK OFFICE

December 4, 2003

Applicant(s) : Gert KOEST

For : OPHTHALMIC REFRACTOMETER AND METHOD OF
OPERATING AN OPHTHALMIC REFRACTOMETER

Atty. Docket No.: BTK Case 379

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is Form PTO-1449 and one copy of DE 30 14 907 which is listed thereon.

More specifically, please note that four references are listed in Applicant's specification (one U.S. patent and three German patents). Two of the three German patents have corresponding U.S. patents. Therefore, Form PTO-1449 lists three U.S. patents. Since this application is being filed after June 30, 2003, Applicant hereby accepts the USPTO waiver of the requirement under 37 CFR 1.98(a)(2)(i) for submitting a copy of each cited U.S. patent [1271 Off. Gaz. Pat. Off. 100, 6/17/2003].

In that no corresponding U.S. patent was found for DE 30 14 907, Applicant is enclosing a copy of the German reference (along with an English abstract thereof). Further comment at this point in time should not be necessary.

Further consideration is respectfully solicited.

Respectfully Submitted,


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Reg. No. 37 714
Reg. No. 53 685
Reg. No. 24 949

Encl: Form PTO-1449 and one copy of DE 30 14 907

INFORMATION
DISCLOSURE
CITATION

Applicant: 'Gert KOEST

Ser.No. : Unknown

Filed : Unknown

Conf. No.: Unknown

Atty.Ref.: BTK Case 379

Group : Unknown

U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Date	Name	Class	Sub Class	Filing Date
	AA	4 410 243	10/18/1983	Fürste		
	AB	4 421 391	12/20/1983	Matsumura et al.		
	AC	4 432 617	02/21/1984	Itoh et al.		
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Sub Class	Translation Yes No
	AL	DE 30 14 907	10/29/1981	GERMANY	English Abstract	Attached.
	AM					
	AN					
	AO					
	AP					

OTHER DOCUMENTS (Including Author, Title, Date, Pages, Etc.)

	AR	
	AS	

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.